

QM1000™ Quad-Site Tester

Low cost, high throughput testing service and product from USEA

Ideal for specialty testing of:

- MOSFETs
- JFETs
- IGBTs
- Diodes
- Mixed signal ICs
- Discrete analog devices



Features:

- Single insertion testing (SIS)
- Quad-site functionality
- Perform DC and specialty AC tests, including Qg, Rg, Cg, and UIL/UIS
- Optional scalable indexed parallel solution (SIPS)
- Compatible with rotary, film frame and auto handlers

Benefits:

- Expands the ASL1000 tester platform's capabilities
- Eliminates the need for multiple external instruments
- Reduces device handling
- Generates actual test data versus go/no-go results
- Up to 4x increase in test throughput

Test Capabilities:

<u>DC</u>	<u>QG</u>	<u>RG/CG</u>	<u>UIL/UIS (Avalanche)</u>
<ul style="list-style-type: none">• Max current = 200 A• Max voltage = 1700 V• < 1 mΩ Rds testing• < 10 nA leakage• Test time dependent on number of tests required by customer	<ul style="list-style-type: none">• Max current = 100 A• Max drain voltage = 150 V• Max gate clamp voltage = ±16 V• Max gate current = 10 mA• Test time = 130 ms	<ul style="list-style-type: none">• Frequency range = 300 kHz to 10 MHz• Capacitance range = 500 pF to 40 nF• Resistance range = 400 mΩ to 100 Ω• Switchable on board circuit or LCR meter• Test time = 120 ms	<ul style="list-style-type: none">• Max current = 200 A• Max drain voltage = 150 V• Drain current range = 0.5 A to 200 A• Selectable inductor ranges (0.1, 0.3, 1, 3, and 10 mH plus a slot for a user-selected inductor)• Test time = 50 ms

Note: Specialty test times may vary depending on exact specifications of device under test

“To be our customers' first and their BEST solution”

